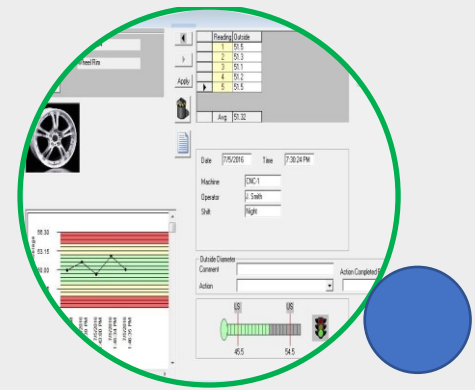


FEATURES

- Data entry while viewing the control chart in real time
- Provides key SPC charts and calculations
- Engineering specifications for each characteristic measured
- Picture of each characteristic measured
- Procedure on how to measure characteristic
- Settings to capture data from external measurement tools
- Custom fields that are user defined
- Multi language support

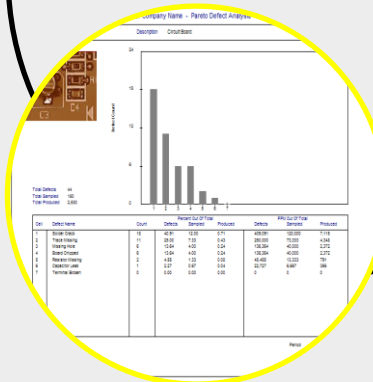
“Measurement Data Collection”



REPORTS

- Control charts (XBar/R, X/MR, MA/MR and XBar/Sigma)
- Capability analysis with histogram
- Cpk summary report for different products
- Pareto analysis of defects
- Excel import/export data
- E-Mail report as pdf file attachment

Multi language support



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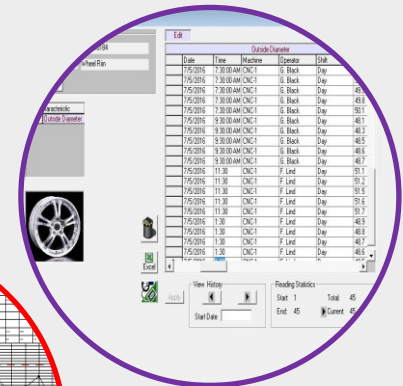
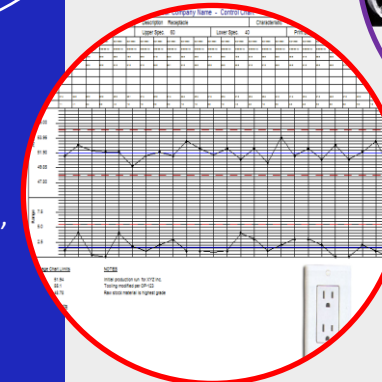
EOmet Technologies India Pvt. Ltd.

Corporate Suite, 2F-26, II Floor, Ansal Plaza, Vaishali, Sector-1, Ghaziabad, India, Zip: 201010

sales@meteq.co.in | www.meteq.co.in/statistical-process-control/

SECURITY

- Password protection for the system
- Language or terminology considerations for screens and reports



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